LISTING OF THE CLAIMS:

This listing of claims replaces all prior versions, and listings, of claims in the application:

1: (Previously Presented) A method for at least partially compensating luminance of an emissive display comprising:

having a desired luminance, as a function of time, for one or more organic light emitting diodes (OLEDs) included in said emissive display;

estimating the amount of degradation of the OLEDs; and

utilizing, at least in part, the estimated amount of degradation, attempting to adjust (adjusting) the luminance of the OLEDs to the desired luminance.

2: (Cancelled)

3: (Previously Presented) The method of claim 1, wherein estimating includes estimating a characteristic substantially correlated with said degradation.

4: (Original) The method of claim 3, wherein said estimating includes measuring the voltage across said one or more OLEDs at a substantially constant current flow through said one or more OLEDs.

5: (Previously Presented) The method of claim 1, wherein measuring said voltage across said one or more organic light emitting diodes (OLEDs) includes measuring the reverse bias resistance of said one or more OLEDs.

6: (Previously Presented) The method of claim 1, wherein adjusting includes adjusting the amount of electrical energy applied to said one or more organic light emitting diodes (OLEDs).

7: (Original) The method of claim 6, wherein adjusting includes increasing the voltage applied across said one or more OLEDs.

8: (Original) The method of claim 7, wherein increasing includes utilization of a lookup table.

9: (Original) The method of claim 8, wherein said lookup table includes values such that the luminance of said one or more organic light emitting diodes (OLEDs) achieved by the adjustment essentially decreases over time.

10: (Previously Presented) The method of claim 1, wherein said method further comprises adjusting the luminance of said one or more organic light emitting diodes (OLEDs) based, at least in part, upon estimating the amount of degradation of one or more other organic light emitting diodes (OLEDs).

11: (Currently Amended) An apparatus comprising:

one or more organic light emitting diodes (OLEDs);

a measurement circuit capable of estimating the amount of degradation of the OLEDs;

and

a control system ~~having a~~ having a desired luminance, as a function of time, for the OLEDs;

wherein the control system is capable of, utilizing at least in part the estimated amount of degradation, attempting to adjust (adjusting) the luminance of the OLEDs to the desired luminance.

12: (Cancelled).

13: (Previously Presented) The apparatus of claim 11, wherein the estimation of the amount of degradation, made by said measurement circuit, includes an estimation of a characteristic substantially correlated with said degradation.

14: (Original) The apparatus of claim 13, wherein said measurement circuit is capable of measuring the reverse bias resistance of said one or more organic light emitting diodes (OLEDs) operating at a substantially constant current.

15: (Previously Presented) The apparatus of claim 11, wherein said control system is capable of adjusting said luminance of said one or more organic light emitting diodes (OLEDs) by adjusting the substantially instantaneous current through said OLEDs.

16: (Previously Presented) The apparatus of claim 11, wherein said control system comprises a series of data that correlates a desired luminance with the estimated degradation of said one or more OLEDs.

17: (Original) The apparatus of claim 16, wherein said control system utilizes said series of data to adjust the luminance of said one or more OLEDs.

18: (Original) The apparatus of claim 17, wherein said control system comprises a series of data that correlates a desired luminance with the estimated degradation of said one or more OLEDs such that said desired luminance decreases as said estimated degradation of said one or more OLEDs increases.

19: (Previously Presented) The apparatus of claim 11, wherein said control system includes a storage medium having a plurality of machine accessible instructions, wherein, when said instructions are executed by said control system, the instructions provide for

utilizing a signal from said measuring circuit;

estimating a desired luminance for said OLEDs; and

adjusting the current applied to said OLEDs based at least in part upon said signal.

Claims 20 – 29: (Cancelled).